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## **Fiberoptik – Kalibrering av avstämbara laserkällor**

*Calibration of tuneable laser sources*

Som svensk standard gäller europastandarden EN 62522:2014. Den svenska standarden innehåller den officiella engelska språkversionen av EN 62522:2014.

### **Nationellt förord**

Europastandarden EN 62522:2014

består av:

- **europastandardens ikraftsättningsdokument**, utarbetat inom CENELEC
- **IEC 62522, First edition, 2014 - Calibration of tuneable laser sources**

utarbetad inom International Electrotechnical Commission, IEC.

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English Version

**Calibration of tuneable laser sources  
(IEC 62522:2014)**

Étalonnage des sources laser accordables  
(CEI 62522:2014)

Kalibrierung von abstimmbaren Laserquellen  
(IEC 62522:2014)

This European Standard was approved by CENELEC on 2014-03-21. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels**

## Foreword

The text of document 86/443/CDV, future edition 1 of IEC 62522, prepared by IEC TC 86 "Fibre optics" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62522:2014.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2015-01-18
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2017-03-21

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## Endorsement notice

The text of the International Standard IEC 62522:2014 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60027-3	NOTE	Harmonised as EN 60027-3.
IEC 60359	NOTE	Harmonised as EN 60359.
IEC 60793-1 (Series)	NOTE	Harmonised in EN 60793-1 (Series)
IEC 60793-2 (Series)	NOTE	Harmonised in EN 60793-2 (Series)
IEC 61280-1-3:2010	NOTE	Harmonised as EN 61280-1-3:2010.
IEC 61300-3-2	NOTE	Harmonised as EN 61300-3-2
IEC 61315	NOTE	Harmonised as EN 61315

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: [www.cenelec.eu](http://www.cenelec.eu)

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60793-2-50	-	Optical fibres -- Part 2-50: Product specifications - Sectional specification for class B single-mode fibres	EN 60793-2-50	-
IEC 60825-1	-	Safety of laser products -- Part 1: Equipment classification and requirements	EN 60825-1	-
IEC 60825-2	-	Safety of laser products -- Part 2: Safety of optical fibre communication systems (OFCS)	EN 60825-2	-
IEC 62129-2	-	Calibration of wavelength/optical frequency measurement instruments -- Part 2: Michelson interferometer single wavelength meters	EN 62129-2	-
ISO/IEC 17025	-	General requirements for the competence of testing and calibration laboratories	EN ISO/IEC 17025	-
ISO/IEC Guide 98-3 2008	-	Uncertainty of measurement -- Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)		-
ISO/IEC Guide 99 2007	-	International vocabulary of metrology -- Basic and general concepts and associated terms (VIM)		-

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**CALIBRATION OF TUNEABLE LASER SOURCES****FOREWORD**

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International Standard IEC 62522 has been prepared by IEC technical committee 86: Fibre optics.

The text of this standard is based on the following documents:

CDV	Report on voting
86/443/CDV	86/459/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.



The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

## INTRODUCTION

Wavelength-division multiplexing (WDM) transmission systems have been deployed in optical trunk lines. ITU-T Recommendations in the G.694 series describe the frequency and wavelength grids for WDM applications. For example, the frequency grid of G.694.1 supports a variety of channel spacing ranging from 12,5 GHz to 100 GHz and wider. WDM devices, such as arrayed waveguide grating (AWG), thin film filter or grating based multiplexers (MUX) and demultiplexers (DMUX) with narrow channel spacing are incorporated in the WDM transmission systems. When measuring the characteristics of such devices, wavelength tuneable laser sources are commonly used and are required to have well-calibrated performances; wavelength uncertainty, wavelength tuning repeatability, wavelength stability and output optical power stability are important parameters.

The tuneable laser source (TLS) is generally equipped with the following features:

- a) the output wavelength is continuously tuneable in a wavelength range starting at 1 260 nm or higher and ending at less than 1 675 nm (the output should excite only the fundamental LP01 fibre mode);
- b) an output port for optical fibre connectors.

The envelope of the spectrum is a single longitudinal mode with a FWHM of at most 0,1 nm. Any adjacent modes are at least 20 dB lower than the main spectral mode (for example, a distributed feedback laser diode (DFB-LD), external cavity laser, etc.)

## CALIBRATION OF TUNEABLE LASER SOURCES

### 1 Scope

This International Standard provides a stable and reproducible procedure to calibrate the wavelength and power output of a tuneable laser against reference instrumentation such as optical power meters and optical wavelength meters (including optical frequency meters) that have been previously traceably calibrated.

### 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60793-2-50, *Optical fibres – Part 2-50: Product specifications – Sectional specification for class B single-mode fibres*

IEC 60825-1, *Safety of laser products – Part 1: Equipment classification and requirements*

IEC 60825-2, *Safety of laser products – Part 2: Safety of optical fibre communication systems (OFCS)*

IEC 62129-2, *Calibration of wavelength/optical frequency measurement instruments – Part 2: Michelson interferometer single wavelength meters*

ISO/IEC 17025, *General requirements for the competence of testing and calibration laboratories*

ISO/IEC Guide 98-3:2008, *Uncertainty of measurement – Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)*

ISO/IEC Guide 99:2007, *International vocabulary of metrology – Basic and general concepts and associated terms (VIM)*